

Description

The μPD43258A is a 32,768-word by 8-bit static RAM fabricated with advanced silicon-gate technology. Its unique design uses CMOS peripheral circuits and N-channel memory cells with polysilicon resistors to make the μPD43258A a high-speed device that requires very low power and no clock or refreshing.

Minimum standby power is drawn when $\overline{CS}$ is high, independent of the other inputs' levels. The μPD43258A is available in standard 28-pin plastic DIP or SOJ packaging.

Features

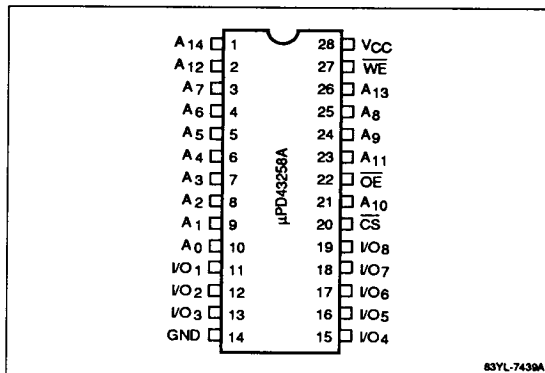
- Single +5-volt power supply
- Fully static operation—no clock or refreshing
- TTL-compatible inputs and outputs
- Common I/O using three-state outputs
- One $\overline{CS}$ pin and one $\overline{OE}$ pin for easy application
- Standard 28-pin plastic DIP and SOJ packaging
- Fast access time of 15 ns (max)

Ordering Information

Part Number	Access Time (max)	Package
μPD43258ACR-15	15 ns	28-pin plastic DIP
CR-20	20 ns	
CR-25	25 ns	
μPD43258ALA-15	15 ns	28-pin plastic SOJ
LA-20	20 ns	
LA-25	25 ns	

Pin Configurations

28-Pin Plastic DIP or SOJ

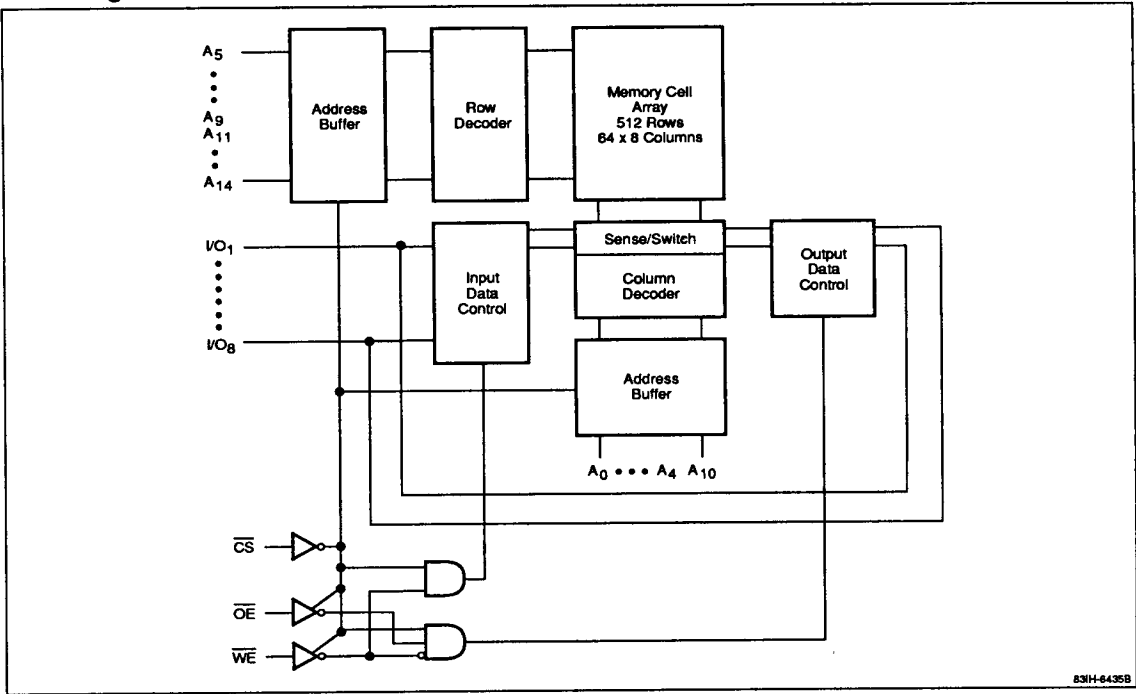


Pin Identification

Symbol	Function
A ₀ - A ₁₄	Address inputs
I/O ₁ - I/O ₈	Data inputs and outputs
$\overline{CS}$	Chip select
$\overline{OE}$	Output enable
$\overline{WE}$	Write enable
GND	Ground
V _{CC}	+5-volt power supply

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Block Diagram



Truth Table

Function	$\overline{CS}$	$\overline{OE}$	$\overline{WE}$	I/O	I_{CC}
Not selected	H	X	X	High-Z	Standby
Outputs disabled	L	H	H	High-Z	Active
Read	L	L	H	D_{OUT}	Active
Write	L	X	L	D_{IN}	Active

Notes:

(1) X = don't care.

Recommended Operating Conditions

Parameter	Symbol	Min	Typ	Max	Unit
Supply voltage	V_{CC}	4.5	5.0	5.5	V
Input voltage, low (Note 1)	V_{IL}	-0.5		0.8	V
Input voltage, high	V_{IH}	2.2		$V_{CC} + 0.3$	V
Ambient temperature	T_A	0		70	°C

Notes:

(1) -3.0 V minimum (pulse width = 10 ns).

DC Characteristics

$T_A = 0 \text{ to } +70^\circ\text{C}$; $V_{CC} = +5.0 \text{ V} \pm 10\%$

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions
Input leakage current	I_{LI}	-2		2	μA	$V_{IN} = 0 \text{ V to } V_{CC}$
I/O leakage current	I_{LO}	-2		2	μA	$V_{IO} = 0 \text{ V to } V_{CC}$; $\overline{CS} \geq V_{IH}$ or $\overline{OE} \geq V_{IH}$ or $\overline{WE} \leq V_{IL}$
Standby supply current	I_{SB}			30	ma	$\overline{CS} \geq V_{IH}$; $V_{IN} = V_{IH}$ or V_{IL}
	I_{SB1}			2	mA	$\overline{CS} \geq V_{CC} - 0.2 \text{ V}$; $V_{IN} \leq 0.2 \text{ V}$ or $\geq V_{CC} - 0.2 \text{ V}$
Output voltage, low	V_{OL}			0.4	V	$I_{OL} = 8 \text{ mA}$
Output voltage, high	V_{OH}	2.4			V	$I_{OH} = -4.0 \text{ mA}$

Absolute Maximum Ratings

Supply voltage, V_{CC} (Note 1)	-0.5 to +7.0 V
Input voltage, V_{IN} (Note 1)	-0.5 to $V_{CC} + 0.5$ V
Output voltage, V_{IO} (Note 1)	-0.5 to $V_{CC} + 0.5$ V
Operating temperature, T_{OPR}	0 to +70°C
Storage temperature, T_{STG}	-55 to +125°C

Exposure to Absolute Maximum Ratings for extended periods may affect device reliability; exceeding the ratings could cause permanent damage. The device should be operated within the limits specified under DC and AC Characteristics.

Notes:

(1) - 3.0 V minimum (pulse width = 10 ns).

AC Characteristics

$T_A = 0$ to +70°C; $V_{CC} = +5.0$ V $\pm$ 10%

Capacitance

$T_A = +25^\circ\text{C}$; $f = 1$ MHz; V_{IN} and $V_{OUT} = 0$ V

Parameter	Symbol	Min	Max	Unit
Input capacitance	C_i		6	pF
Input/output capacitance	C_{IO}		8	pF

Notes:

(1) This parameter is sampled and not 100% tested.

Parameter	Symbol	μPD43258A-15		μPD43258A-20		μPD43258A-25		Unit	Test Conditions
		Min	Max	Min	Max	Min	Max		
Read Operation									
Operating supply current	I _{CC}		150		140		130	mA	$\overline{CS} \leq V_{IL}$ (min cycle); I _{IO} = 0 mA
Read cycle time	t _{RC}	15		20		25		ns	(Note 2)
Address access time	t _{AA}		15		20		25	ns	(Note 2)
Chip select access time	t _{ACS}		15		20		25	ns	(Note 2)
Output enable to output valid	t _{OE}		9		10		12	ns	(Note 2)
Output hold from address change	t _{OH}	3		3		3		ns	(Note 2)
Chip select to output in low-Z	t _{CLZ}	3		3		3		ns	(Note 3)
Output enable to output in low-Z	t _{OLZ}	0		0		0		ns	(Note 3)
Chip select to output in high-Z	t _{CHZ}		10		10		10	ns	(Note 3)
Output enable to output in high-Z	t _{OHZ}		8		8		10	ns	(Note 3)
Write Operation									
Write cycle time	t _{WC}	15		20		25		ns	
Chip select to end of write	t _{CW}	12		13		15		ns	
Address valid to end of write	t _{AW}	12		13		15		ns	
Address setup time	t _{AS}	0		0		0		ns	
Write pulse width	t _{WP}	12		13		15		ns	
Write recovery time	t _{WR}	0		0		0		ns	
Data valid to end of write	t _{DW}	9		10		12		ns	
Data hold time	t _{DH}	0		0		0		ns	
Write enable to output in high-Z	t _{WHZ}		8		8		10	ns	(Note 3)
Output active from end of write	t _{OW}	0		0		0		ns	(Note 3)

Notes:

- (1) Input pulse levels = 0 to 3 V; input pulse rise and fall times = 5 ns; timing reference levels = 1.5 V.
- (2) See figure 1 for output load.
- (3) See figure 2 for output load.

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Figure 1. Output Load

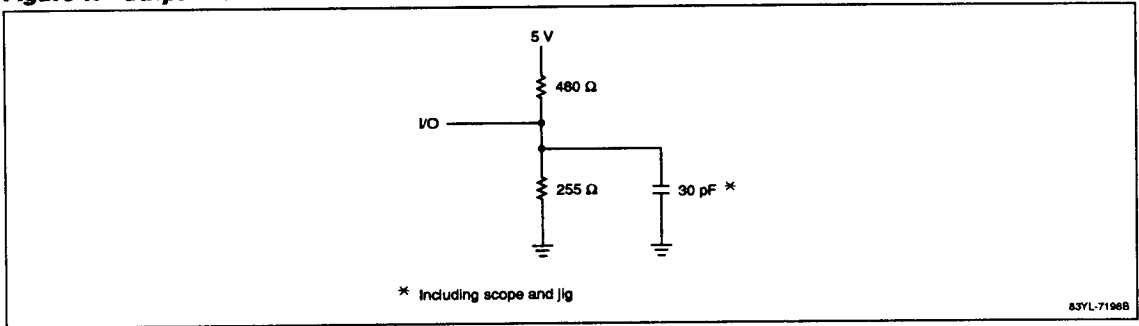
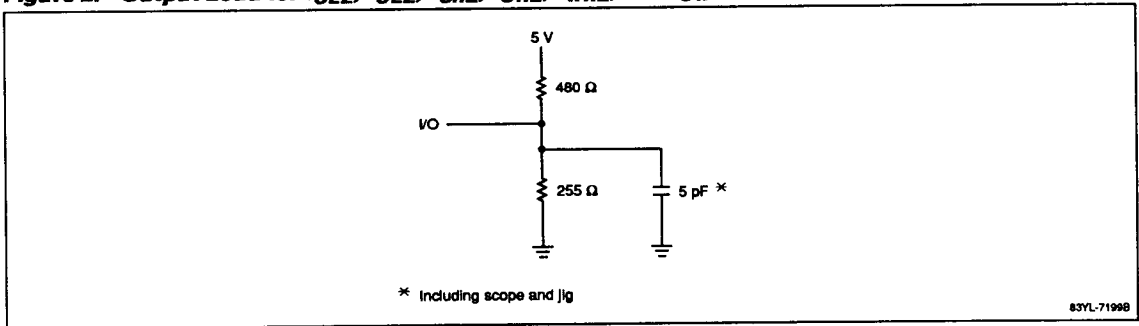
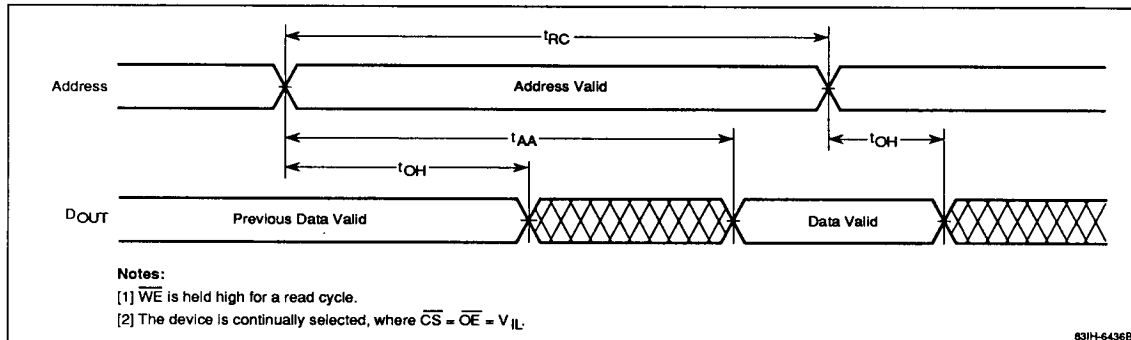


Figure 2. Output Load for t_{CLZ} , t_{OLZ} , t_{CHZ} , t_{OHZ} , t_{WHZ} , and t_{OW}

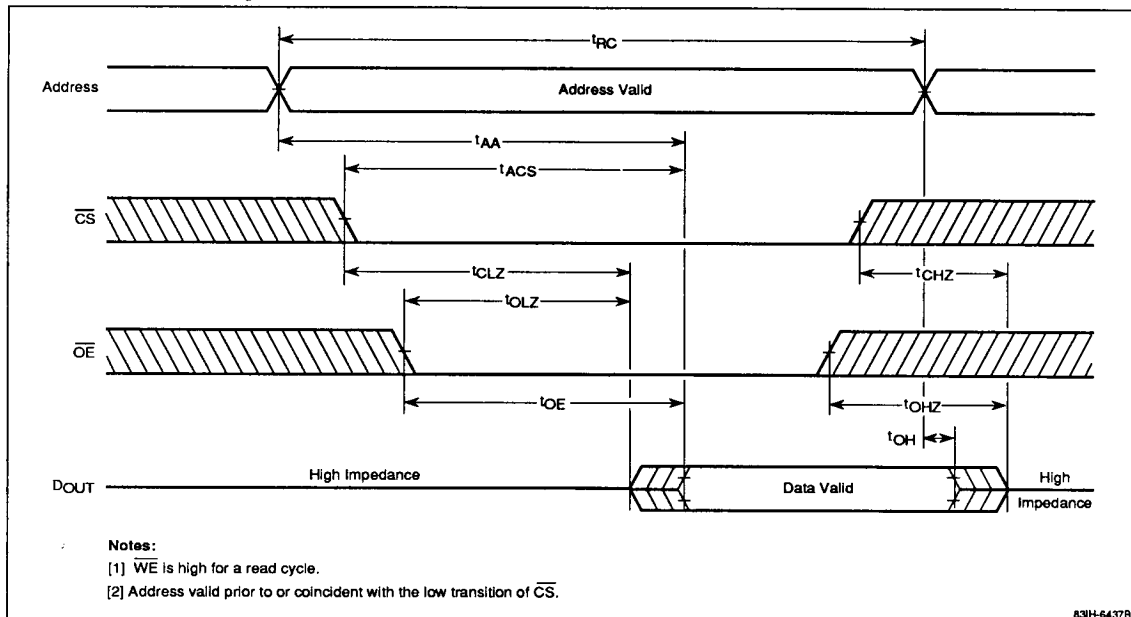


Timing Waveforms

Address Access Cycle



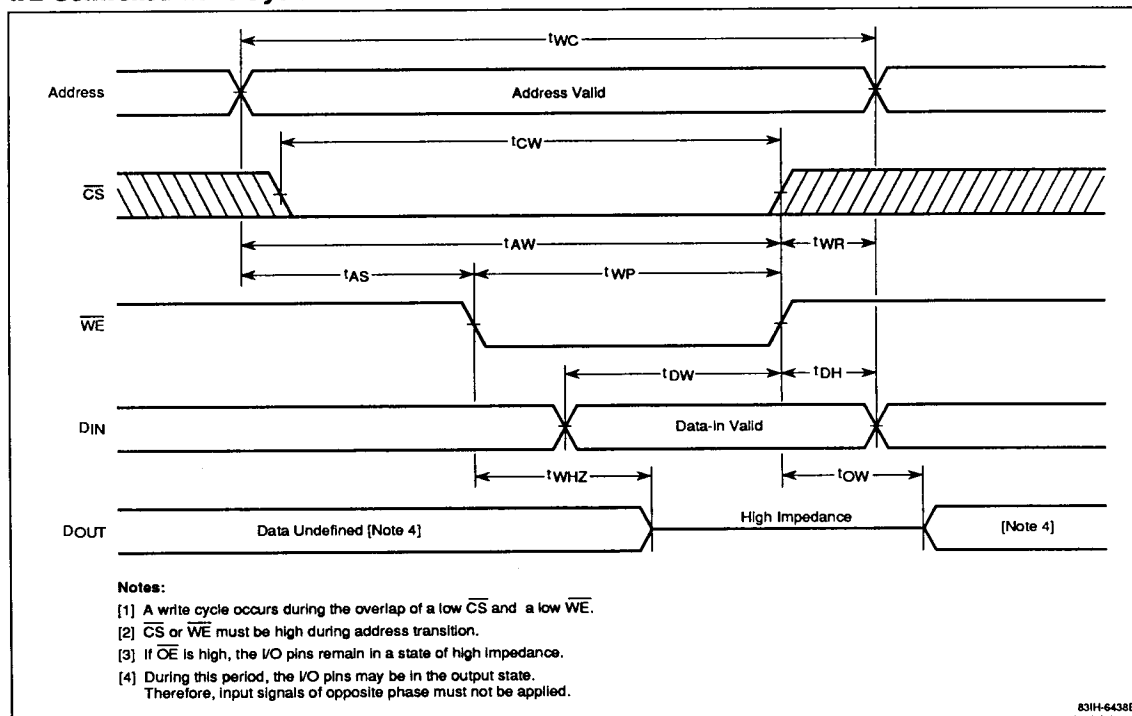
Chip Select Access Cycle



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Timing Waveforms (cont)

WE-Controlled Write Cycle



Timing Waveforms (cont)

$\overline{CS}$ -Controlled Write Cycle

